

Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ unless otherwise noted)

- Channel 1

Symbol	Parameter		Rating	Unit
Common Ratings				
V _{DSS}	Drain-Source Voltage		60	V
V _{GSS}	Gate-Source Voltage		±20	
T _J	Maximum Junction Temperature		150	°C
T _{STG}	Storage Temperature Range		-55 to 150	
I _S	Diode Continuous Forward Current	T _A =25°C	0.1	A
I _D	Continuous Drain Current	T _A =25°C	0.26	A
		T _A =70°C	0.21	
I _{DM} ^a	Pulsed Drain Current	T _A =25°C	1	A
P _D	Maximum Power Dissipation	T _A =25°C	0.25	W
		T _A =70°C	0.16	
R _{θJA} ^b	Thermal Resistance-Junction to Ambient	Steady State	500	°C/W

- Channel 2

Symbol	Parameter		Rating	Unit
Common Ratings				
V _{RRM}	Peak Repetitive Reverse Voltage		40	V
V _{RWM}	Working Peak Reverse Voltage		40	
V _R	DC Reverse Voltage		40	V
V _{RMS}	RMS Reverse Voltage		28	V
I _S	Diode Continuous Forward Current	T _A =25°C	0.35	A
I _{SM} ^a	Non-Repetitive Peak Forward Current	T _A =25°C	1.5	A
P _D	Maximum Power Dissipation	T _A =25°C	0.25	W
		T _A =70°C	0.16	
R _{θJA} ^b	Thermal Resistance-Junction to Ambient		500	°C/W

Note a : Pulse width limited by max. junction temperature.

Note b : Surface Mounted on 1in² pad area.

Electrical Characteristics (T_A = 25°C unless otherwise noted)

• Channel 1

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =250μA	60	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =48V, V _{GS} =0V T _J =85°C	-	-	1 30	μA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250μA	1	2	2.5	V
I _{GSS}	Gate Leakage Current	V _{GS} =±20V, V _{DS} =0V	-	-	±10	μA
R _{DS(ON)} ^d	Drain-Source On-state Resistance	V _{GS} =10V, I _{DS} =100mA V _{GS} =4.5V, I _{DS} =50mA	-	1.8 2	2.2 2.6	Ω
Diode Characteristics						
V _{SD} ^c	Diode Forward Voltage	I _{SD} =100mA, V _{GS} =0V	-	0.8	1.3	V
t _{rr}	Reverse Recovery Time	I _{SD} =1A, dI _{SD} /dt=100A/μs	-	13	-	ns
Q _{rr}	Reverse Recovery Charge		-	8	-	nC
Dynamic Characteristics ^c						
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =30V, Frequency=1.0MHz	-	24	32	pF
C _{oss}	Output Capacitance		-	5.5	-	
C _{rss}	Reverse Transfer Capacitance		-	2.5	-	
t _{d(ON)}	Turn-on Delay Time	V _{DD} =30V, R _L =300Ω, I _{DS} =0.1A, V _{GEN} =10V, R _G =6Ω	-	3	6	ns
t _r	Turn-on Rise Time		-	7	13	
t _{d(OFF)}	Turn-off Delay Time		-	10	18	
t _f	Turn-off Fall Time		-	12	22	
Gate Charge Characteristics ^d						
Q _g	Total Gate Charge	V _{DS} =30V, V _{GS} =10V, I _{DS} =1A	-	1.6	2.3	nC
Q _{gs}	Gate-Source Charge		-	0.6	-	
Q _{gd}	Gate-Drain Charge		-	0.1	-	

Electrical Characteristics (Cont.)

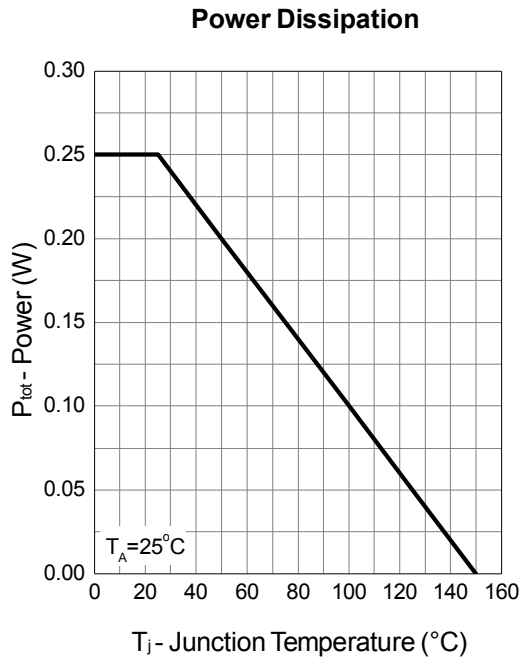
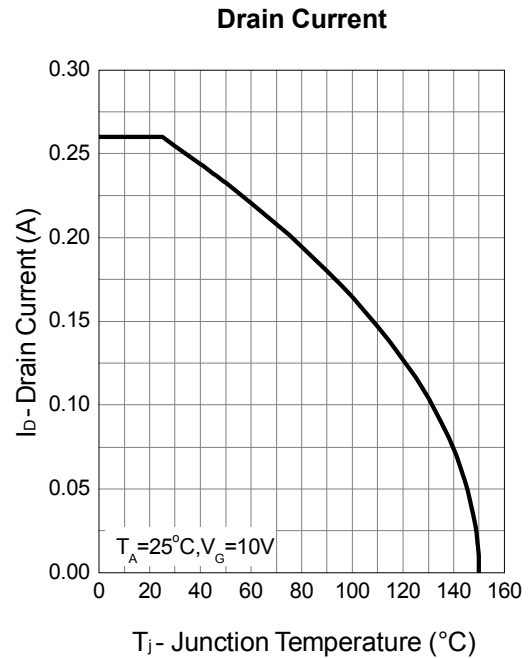
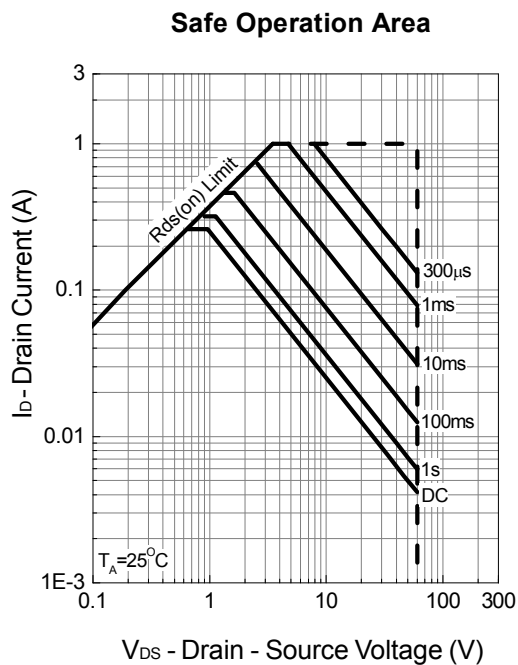
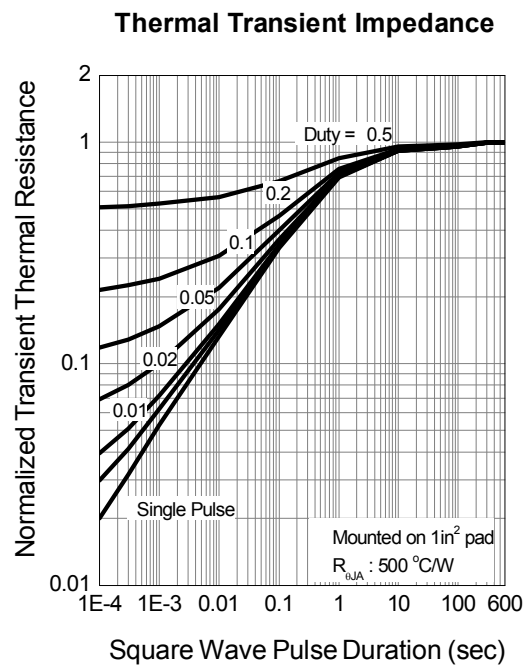
- Channel 2

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Diode Characteristics						
V_{BR}	Reverse Breakdown Voltage	$I_{BR}=250\mu A$	40	-	-	V
V_F^c	Diode Forward Voltage	$I_F=0.02A$	-	-	0.4	V
		$I_F=0.2A$	-	-	0.6	V
I_R	Reverse Current	$V_{BR}=32V$	-	-	5	μA
C_T	Total Capacitance	$V_{BR}=20V$, Frequency=1.0MHz	-	4.6	-	pF
t_{rr}	Reverse Recovery Time	$I_F=1A$, $dI_F/dt=100A/\mu s$,	-	4.1	-	ns
Q_{rr}	Reverse Recovery Charge	$V_{BR}=25V$	-	1	-	nC

Note c : Pulse test ; pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.

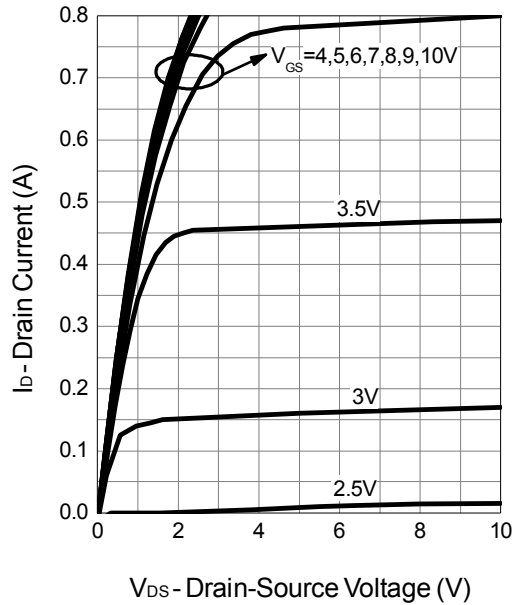
Note d : Guaranteed by design, not subject to production testing.

Channel 1 Typical Operating Characteristics

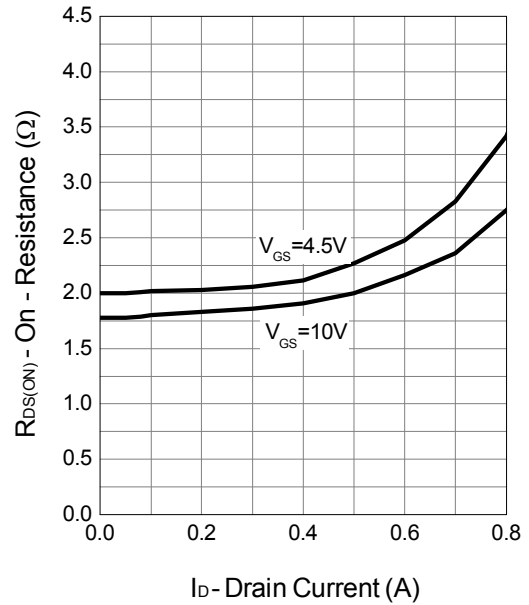


Channel 1 Typical Operating Characteristics (Cont.)

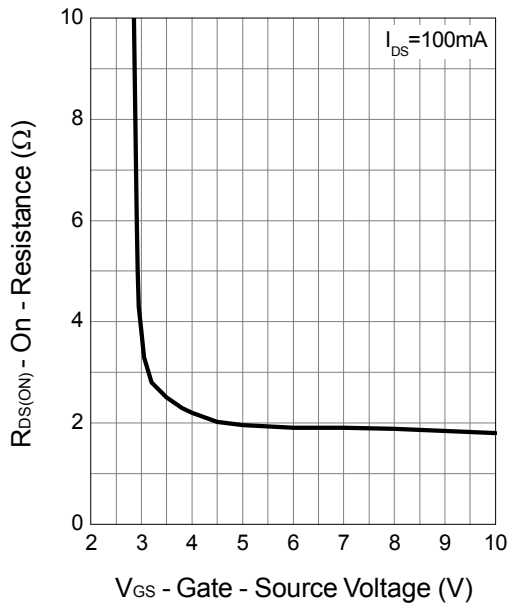
Output Characteristics



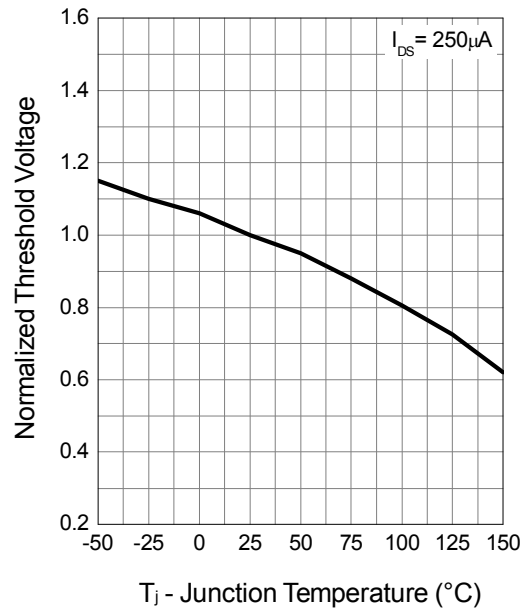
Drain-Source On Resistance



Gate-Source On Resistance

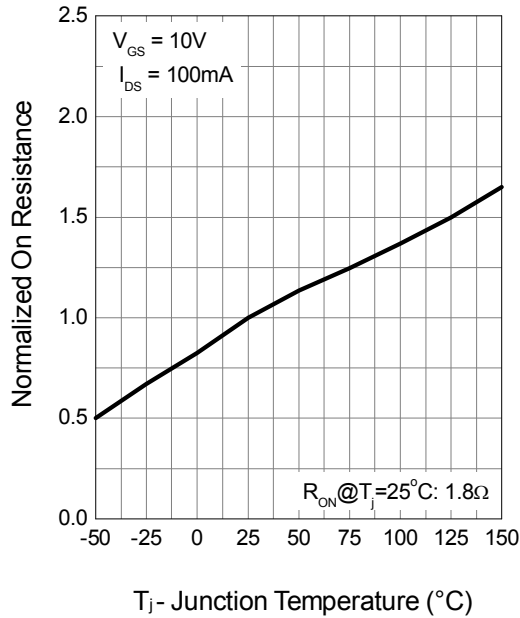


Gate Threshold Voltage

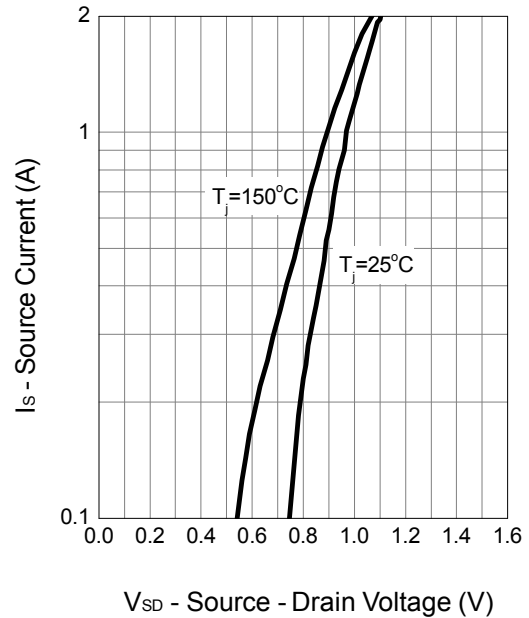


Channel 1 Typical Operating Characteristics (Cont.)

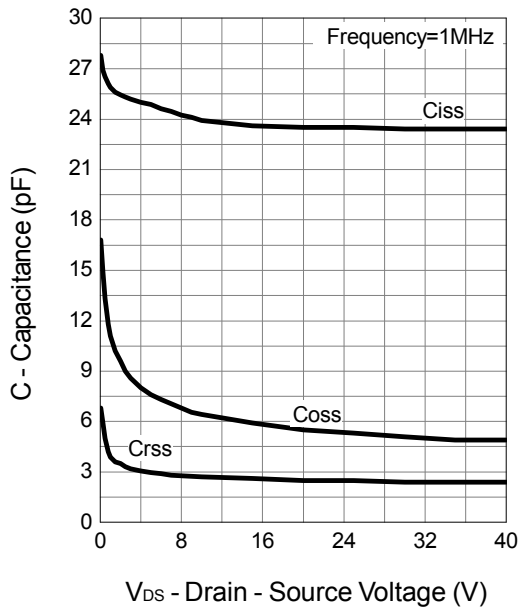
Drain-Source On Resistance



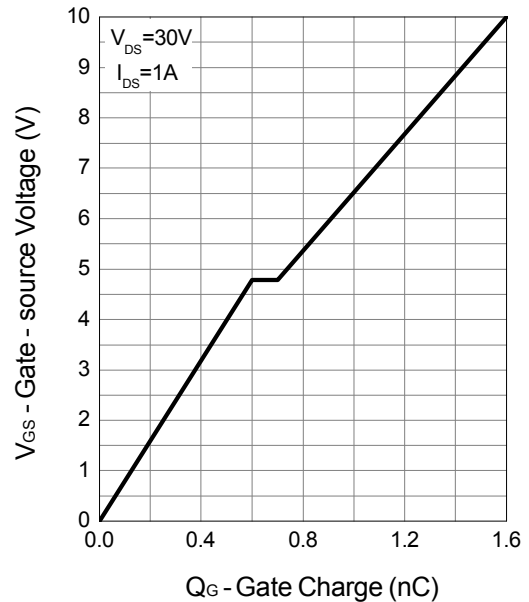
Source-Drain Diode Forward



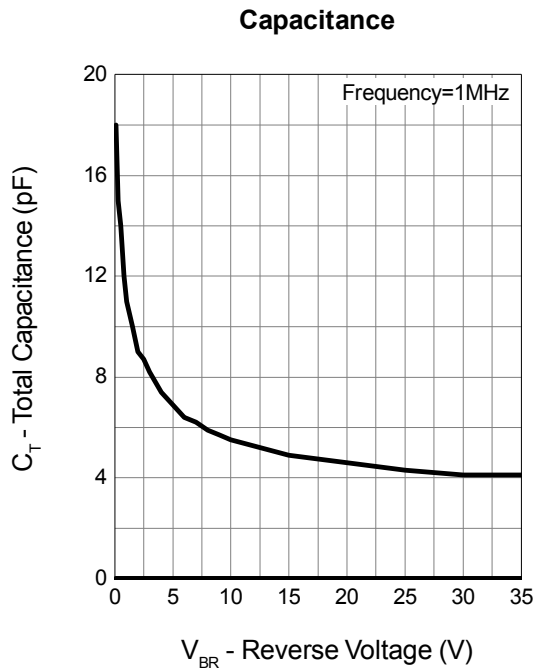
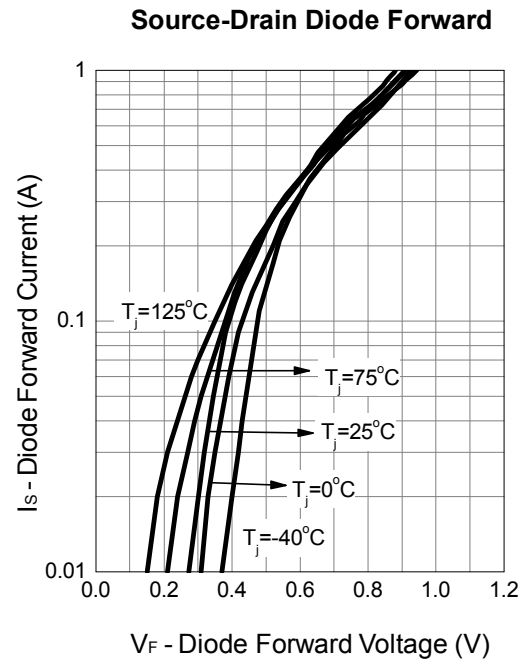
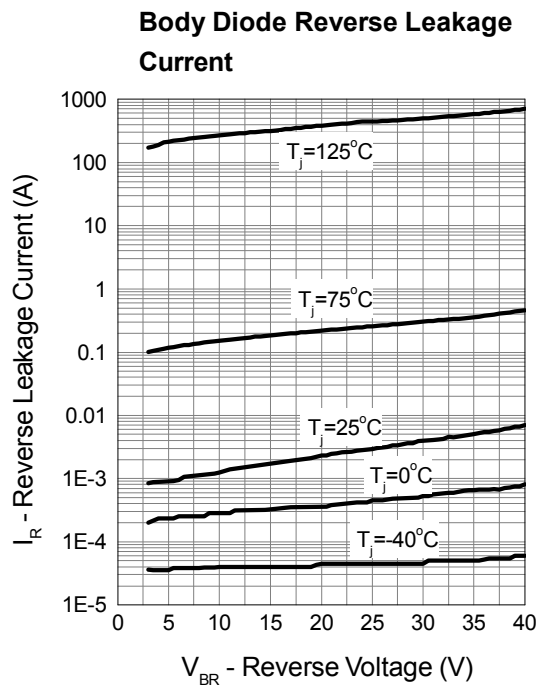
Capacitance



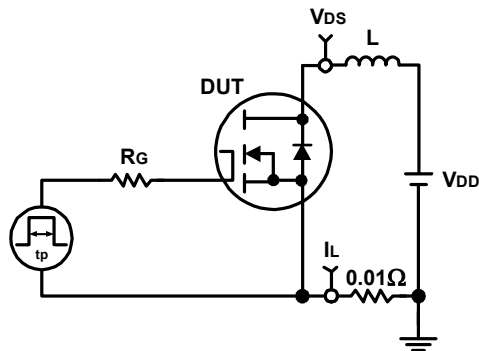
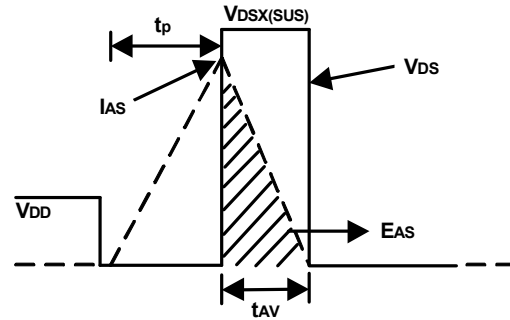
Gate Charge



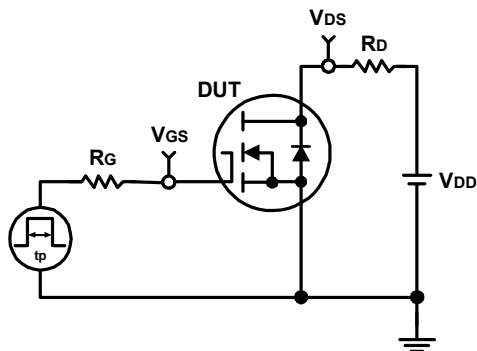
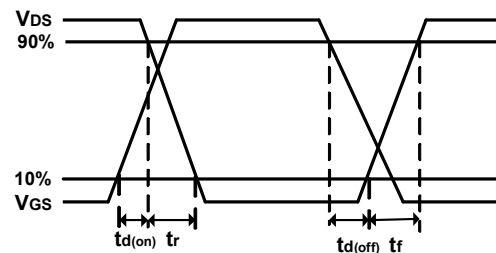
Channel 2 Typical Operating Characteristics



Avalanche Test Circuit and Waveforms



Switching Time Test Circuit and Waveforms



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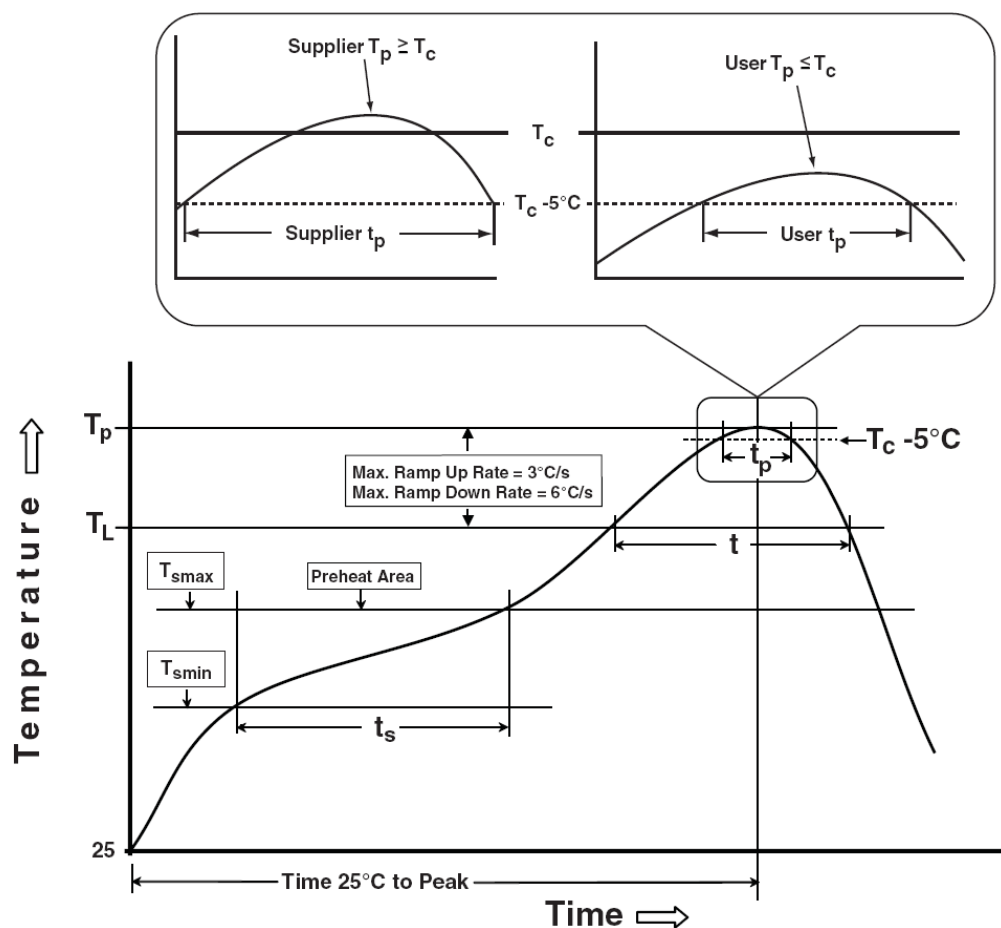
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Classification Profile



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Preheat & Soak Temperature min (T_{smin}) Temperature max (T_{smax}) Time (T_{smin} to T_{smax}) (t_s)	100 °C 150 °C 60-120 seconds	150 °C 200 °C 60-120 seconds
Average ramp-up rate (T_{smax} to T_p)	3 °C/second max.	3°C/second max.
Liquidous temperature (T_L) Time at liquidous (t_L)	183 °C 60-150 seconds	217 °C 60-150 seconds
Peak package body Temperature (T_p)*	See Classification Temp in table 1	See Classification Temp in table 2
Time (t_p)** within 5°C of the specified classification temperature (T_c)	20** seconds	30** seconds
Average ramp-down rate (T_p to T_{smax})	6 °C/second max.	6 °C/second max.
Time 25°C to peak temperature	6 minutes max.	8 minutes max.
* Tolerance for peak profile Temperature (T_p) is defined as a supplier minimum and a user maximum. ** Tolerance for time at peak profile temperature (t_p) is defined as a supplier minimum and a user maximum.		

Table 1. SnPb Eutectic Process – Classification Temperatures (T_c)

Package Thickness	Volume mm ³ <350	Volume mm ³ ≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2. Pb-free Process – Classification Temperatures (T_c)

Package Thickness	Volume mm ³ <350	Volume mm ³ 350-2000	Volume mm ³ >2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HTRB	JESD-22, A108	1000 Hrs, 80% of VDS max @ T_{jmax}
HTGB	JESD-22, A108	1000 Hrs, 100% of VGS max @ T_{jmax}
PCT	JESD-22, A102	168 Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -65°C~150°C

Customer Service

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